

Image  
DOCKET NO. 220033US2



2877

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

Fuyuhiko INOUE, et al.

SERIAL NUMBER: 10/080,537

FILED: February 25, 2002

FOR: WAVEFRONT ABERRATION MEASURING METHOD AND UNIT,  
EXPOSURE APPARATUS, DEVICE MANUFACTURING METHOD,  
AND DEVICE

**STATUS REQUEST**

Honorable Commissioner of Patents & Trademarks  
Alexandria, Virginia 22313

SIR:

The Patent Office is respectfully requested to advise the undersigned of the approximate date a first Official Action will be issued in this Application.

A duplicate of this request and a prepaid return envelope are enclosed for your convenience.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,  
MAIER & NEUSTADT, P.C.

Marvin J. Spivak  
Attorney of Record  
Registration No. 24,913



**22850**

(703) 413-3000  
Fax: (703) 413-2220

Surinder Sachar  
Registration No. 34,423